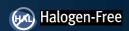
EPC2029 – Enhancement Mode Power Transistor

 V_{DS} , 80 V $R_{DS(on)}\,,\;3.2\,m\Omega$ I_D, 48 A









Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R_{DS(on)}, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR}. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

	Maximum Ratings					
	PARAMETER	VALUE	UNIT			
\ \ \	Drain-to-Source Voltage (Continuous)		V			
V _{DS}	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	96	V			
I _D	Continuous ($T_A = 25$ °C, $R_{\theta JA} = 9$ °C/W)	48	Α			
	Pulsed (25°C, T _{PULSE} = 300 μs)	360	А			
.,	Gate-to-Source Voltage	6	V			
V _{GS}	Gate-to-Source Voltage	-4	V			
TJ	Operating Temperature	g Temperature -40 to 150				
T _{STG}	Storage Temperature	-40 to 150				

			(2)	(2)
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	9	9	9	9
	(3)	9	9	(9)
9	(2)	9	(3)	(3)

EPC2029 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 4.6 mm x 2.6 mm

- High Speed DC-DC Conversion
- · Motor Drive
- Industrial Automation
- Synchronous Rectification
- · Class-D Audio



	Thermal Characteristics					
	PARAMETER TYP UNIT					
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.45				
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	3.9	°C/W			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	45				

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. $See \ https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf \ for \ details.$

Static Characteristics ($T_j = 25^{\circ}$ C unless otherwise stated)						
PARAMETER TEST CONDITIONS MIN TYP MAX UNIT						
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 0.9 \text{ mA}$	80			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 64 \text{ V}$		0.1	0.6	mA
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		1	9	mA
I _{GSS}	Gate-to-Source Reverse Leakage	V _{GS} = -4 V		0.1	0.6	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 12 \text{ mA}$	0.8	1.4	2.5	V
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_D = 30 \text{ A}$		2.5	3.2	mΩ
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.6		V

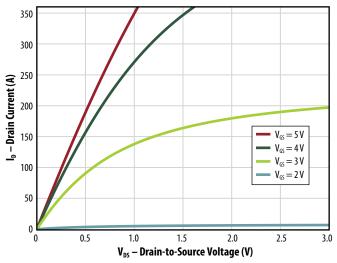
All measurements were done with substrate connected to source.

Dynamic Characteristics (T _J = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			1410	1690	
C_{RSS}	Reverse Transfer Capacitance	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		17		
Coss	Output Capacitance			820	1230	pF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V 0+240VV 0V		1090		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)	$V_{DS} = 0$ to 40 V, $V_{GS} = 0$ V		1310		
R_{G}	Gate Resistance			0.4		Ω
Q _G	Total Gate Charge	$V_{DS} = 40 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 30 \text{ A}$		13	16	
Q _{GS}	Gate-to-Source Charge			3.4		
Q_{GD}	Gate-to-Drain Charge	$V_{DS} = 40 \text{ V}, I_D = 30 \text{ A}$		1.9		
Q _{G(TH)}	Gate Charge at Threshold			2.5		nC
Qoss	Output Charge	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		53	80	
Q _{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C



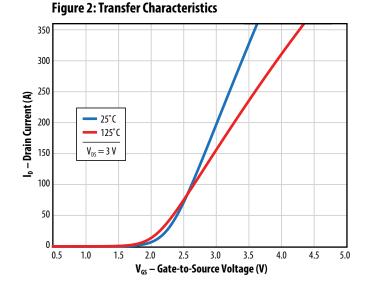


Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents

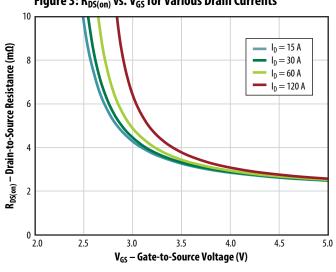
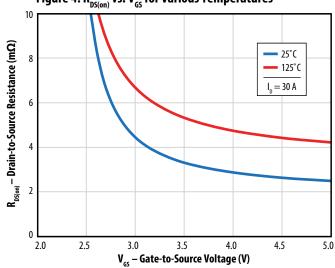


Figure 4: $\mathbf{R}_{\mathrm{DS(on)}}$ vs. \mathbf{V}_{GS} for Various Temperatures



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Note 3: C_{OSS(TR)} is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 5a: Capacitance (Linear Scale)

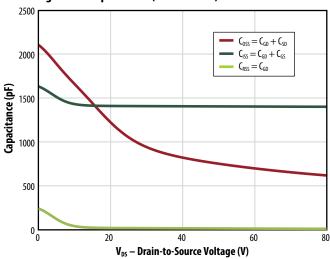


Figure 5b: Capacitance (Log Scale)

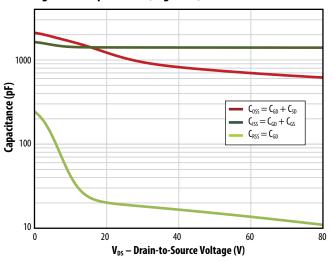


Figure 6: Gate Charge

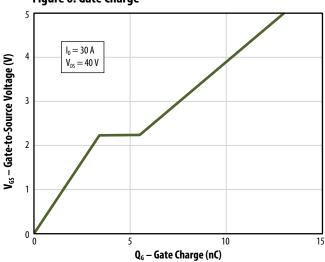


Figure 7: Reverse Drain-Source Characteristics

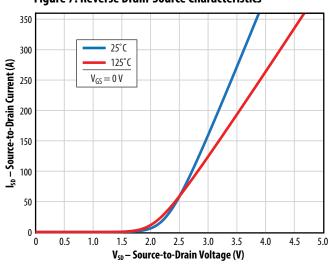


Figure 8: Normalized On-State Resistance vs. Temperature

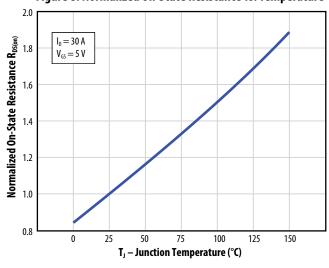
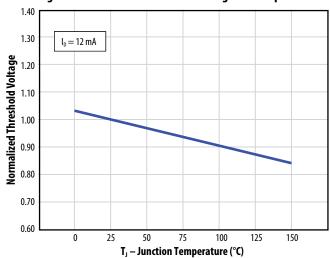


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shortened to source.

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V_{GS} – Gate-to-Source Voltage (V)

Figure 11: Safe Operating Area

1000

Limited by R_{DS(on)}

Pulse Width

100 ms

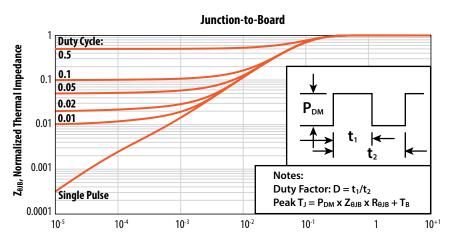
1 ms

1 ms

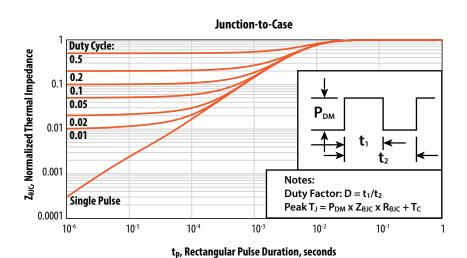
100 μs

V_{DS} - Drain-Source Voltage (V)

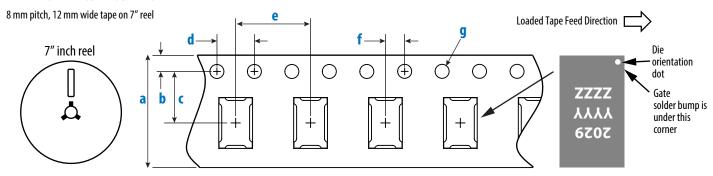
Figure 12: Transient Thermal Response Curves



t_p, Rectangular Pulse Duration, seconds



TAPE AND REEL CONFIGURATION



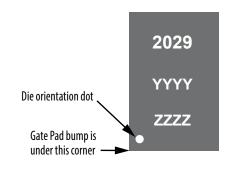
	Dimension (mm)		
EPC2029 (Note 1)	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
е	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

Die is placed into pocket solder bump side down (face side down)

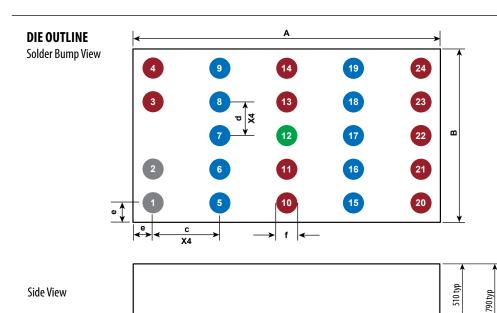
Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

DIE MARKINGS



Dout	Laser Markings			
Part Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3	
EPC2029	2029	YYYY	ZZZZ	



DIM	Micrometers			
DIM	MIN	Nominal	MAX	
Α	4570	4600	4630	
В	2570	2600	2630	
C	1000	1000	1000	
d	500	500	500	
e	285	300	315	
f	332	369	406	

Pads 1 and 2 are Gate;

Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;

Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are

Source;

280+/-28

Pad 12 is Substrate*

*Substrate pin should be connected to Source

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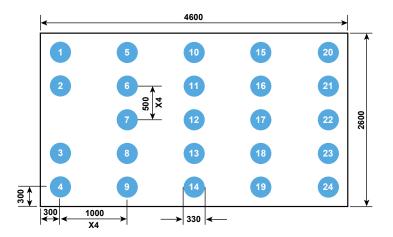
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Seating plane

RECOMMENDED LAND PATTERN

(units in μ m)



Land pattern is solder mask defined Solder mask opening is 330 µm It is recommended to have on-Cu trace PCB vias

Pads 1 and 2 are Gate;

Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;

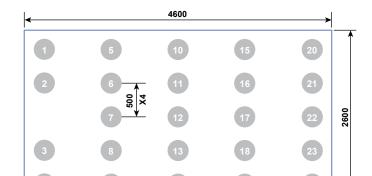
Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;

Pad 12 is Substrate*

*Substrate pin should be connected to Source

RECOMMENDED STENCIL DRAWING

(units in μ m)



Recommended stencil should be 4 mil (100 μ m) thick, must be laser cut, openings per drawing.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx

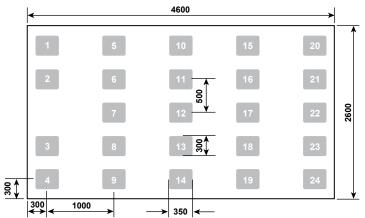
RECOMMENDED STENCIL DRAWING

(units in µm)

Option 2: Intended for use with SAC305 Type 3 solder.

1000

Option 1: Intended for use with SAC305 Type 4 solder.



Recommended stencil should be 4 mil (100 μ m) thick, must be laser cut, openings per drawing.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx

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Revised April, 2021